

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO.

826.1767

APPLICATION NO.

FIRST NAMED INVENTOR

Kwame Osei BOATENG

FILING DATE

November 5, 2001

GROUP ART UNIT

2825

1542 U.S. PTO
09/085768

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
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OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

VS	AM	K. O. Boateng, H. Takahashi and Y. Takamatsu, "Diagnosing Delay Faults in Combinational Circuits Under the Ambiguous Delay Model," IEICE Transaction on Information and Systems, Vol. E82-D, No. 12, pp. 1563-1571. Dec 1999.
VS	AN	K. O. Boateng, H. Takahashi, and Y. Takamatsu, "Multiple Gate Delay Fault Diagnosis Using Test-Pairs for Marginal Delays," IEIEC Transaction on Information and Systems, Vol. E81-D, No. 7, pp. 706-715. July 1998.
VS	AO	N. Yanagida, H. Takahashi and Y. Takamatsu, "Multiple Fault Diagnosis By Sensitizing Input Pairs," IEEE Design and Test of Computers, Vol. 12, No. 3, pp. 44-52. No date

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DATE CONSIDERED

6/14/05

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>	ATTORNEY DOCKET NO. 826.1767	APPLICATION NO. 109/985768
	FIRST NAMED INVENTOR Kwame Osei BOATENG	
	FILING DATE November 5, 2001	GROUP ART UNIT 2820
	10542 U.S. PTO 11/06/01	

U.S. PATENT DOCUMENTS

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1998

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17	AM	M. S. Hsiao and S. T. Chakradhar, "Partitioning and Reordering Techniques for Static Test Sequence Compaction of Sequential Circuits," Proceedings of the 7 th IEEE Asian Test Symposium, pp. 452-457. 1998.
VS	AN	M. S. Hsiao and S. T. Chakradhar, "State Relaxation Based Subsequence Removal for Fast Static Compaction in Sequential Circuits," Proceedings of Design, Automation, and Test in Europe Conf., pp. 557-582. 1998
VS	AO	M. S. Hsiao and E. M. Rudnick and J. H. Patel, "Fast Algorithms For Static Compaction of Sequential Circuit Test Vectors," Proceedings of IEEE VLSI Test Symposium, pp. 188-195. 1999

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